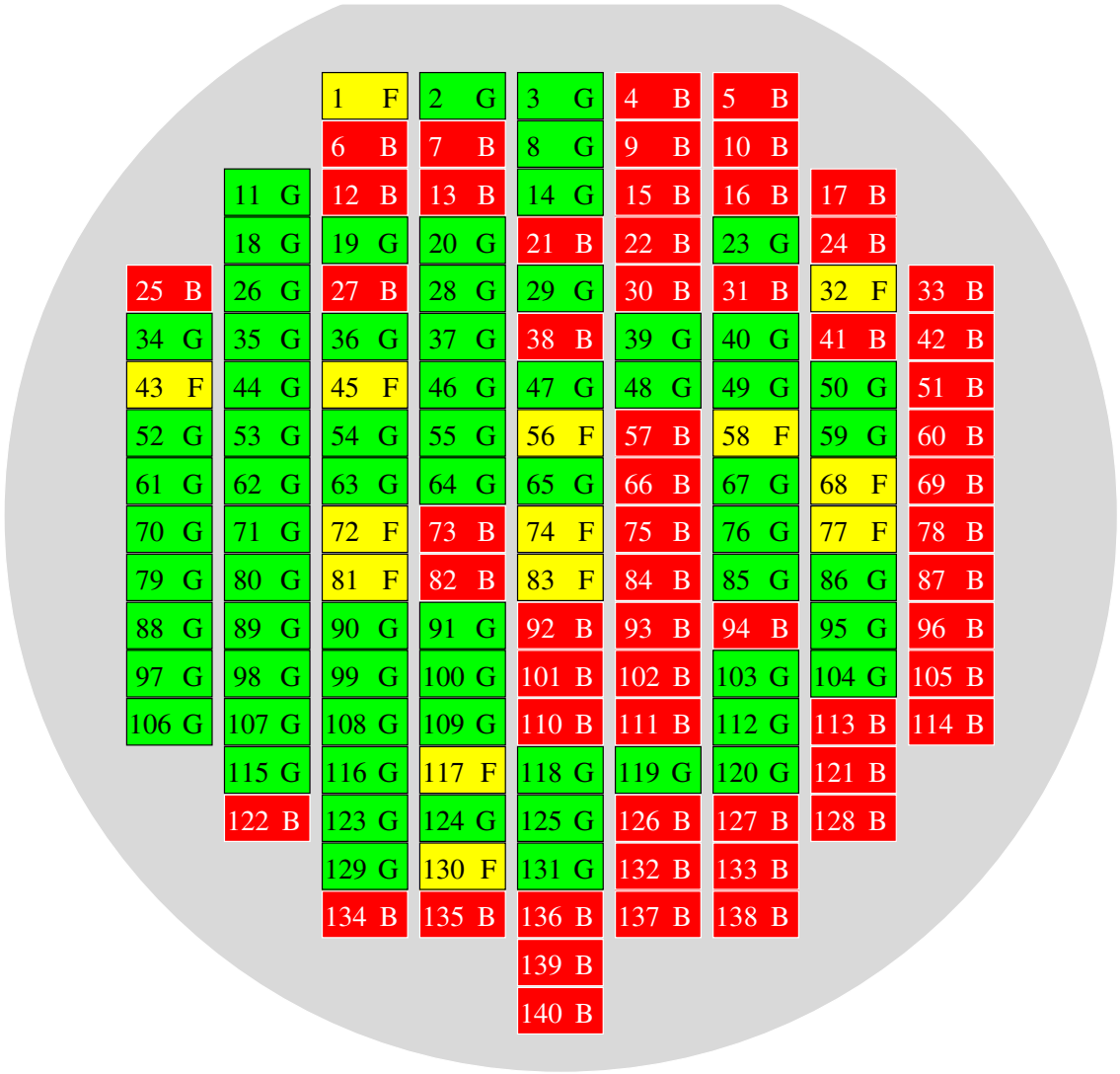
Die quality map for wafer 247 s/n: Y21316-08-09

Date: 12/22/99



# B	Bad die
# F	Fair die
# G	Good die
# N	No info
# *	Manually tagged